CLAIMS

What is claimed is.

- 1 1. A process comprising:
- dispensing a polymer stress-relief layer upon a substrate lower surface under
- 3 conditions to partially embed an electrical first bump disposed upon the lower
- 4 surface; and
- 5 curing the stress-relief layer.
- 1 2. The process of claim 1, following curing the stress-relief layer, further
- 2 including reflowing the electrical first bump.
- 1 3. The process of claim 1, wherein dispensing a polymer includes dispensing in
- 2 a continuous action.
- 1 4. The process of claim 1, wherein dispensing the polymer stress-relief layer
- 2 includes forming a substantially continuous stress-relief layer film between the
- 3 electrical first bump and an electrical second bump that is spaced apart and adjacent
- 4 to the electrical first bump.
- 1 5. The process of claim 1, wherein dispensing the polymer stress-relief layer
- 2 includes forming a substantially continuous stress-relief layer film between the
- 3 electrical first bump and a plurality of electrical subsequent bumps in excess of two,
- 4 at least one of which is spaced apart and adjacent to the electrical first bump.
- 1 6. The process of claim 1, wherein dispensing the polymer stress-relief layer
- 2 includes ejecting a substantially continuous polymer mass upon the lower surface
- 3 that includes a ball grid array in excess of four electrical bumps including the
- 4 electrical first bump.

- The process of claim 1, wherein dispensing the polymer stress-relief layer
- 2 includes ejecting a discrete series of quanta of polymer masses upon the lower
- 3 surface that includes a ball grid array in excess of four electrical bumps including
- 4 the electrical first bump.
- 1 8. The process of claim 1, wherein dispensing the polymer stress-relief layer
- 2 includes ejecting a polymer first mass and a polymer second mass upon the lower
- 3 surface that includes a ball grid array of at least six electrical bumps:
- 4 wherein the electrical first bump is in a rectangular pattern with an electrical
- 5 second bump, an electrical third bump, and an electrical fourth bump, wherein the
- 6 polymer first mass is ejected contiguous with only the electrical first bump, the
- 7 electrical second bump, the electrical third bump, and the electrical fourth bump;
- 8 and
- 9 wherein the electrical first bump and the electrical second bump are in a
- 10 rectangular pattern with an electrical fifth bump and an electrical sixth bump,
- wherein the polymer second mass is ejected contiguous with only the electrical first
- bump, the electrical second bump, the electrical fifth bump, and the electrical sixth
- 13 bump.
- 1 9. The process of claim 1, wherein the electrical first bump includes a first
- 2 height, and wherein dispensing the polymer stress-relief layer includes dispensing in
- a depth range against the electrical first bump in a range from about 5 percent the
- 4 first height to about 95 percent the first height.
- 1 10. An article comprising:
- a mounting substrate including a lower and an upper surface;
- an electrical first bump disposed on the lower surface;
- a stress-relief layer disposed on the lower surface, wherein the electrical first
- 5 bump is at least partially embedded in the stress-relief layer, and wherein at least a
- 6 portion of the electrical first bump is exposed below the stress-relief layer; and

- 7 a die disposed upon the upper surface that is coupled to the electrical first
- 8 bump.
- 1 11. The article of claim 10, wherein the stress-relief layer includes an organic
- 2 material.

1

- 1 12. The article of claim 10, wherein the stress-relief layer includes an organic
- 2 material, and wherein the organic material includes a filler particulate.
- 1 13. The article of claim 10, wherein the stress-relief layer includes a first stress-
- 2 relief layer, wherein the first stress-relief layer is disposed between the electrical
- 3 first bump, an electrical second bump that is spaced apart and adjacent to the
- 4 electrical first bump, an electrical third bump that is spaced apart and adjacent to the
- 5 electrical first bump, and an electrical fourth bump that is spaced apart and adjacent
- 6 to the electrical first bump, the stress-relief layer further including:
- 7 a second stress-relief layer disposed between the electrical first bump and an
- 8 electrical fifth bump that is spaced apart and adjacent to the electrical first bump.
- 1 14. The article of claim 10, wherein the electrical first bump is in a rectangular
- 2 pattern with an electrical second bump, an electrical third bump, and an electrical
- 3 fourth bump, and wherein the stress-relief layer is disposed in about the geometric
- 4 center of the rectangular pattern.
- 1 15. The article of claim 10, wherein the electrical first bump is in a rectangular
- 2 pattern with an electrical second bump, an electrical third bump, and an electrical
- fourth bump, and wherein the stress-relief layer is disposed contiguous with only the
- 4 electrical first bump, the electrical second bump, the electrical third bump, and the
- 5 electrical fourth bump.

- 1 16. The article of claim 10, wherein the polymer stress-relief layer includes a
- 2 polymer first mass and a polymer second mass disposed upon the lower surface that
- 3 includes a ball grid array of at least six electrical bumps:
- 4 wherein the electrical first bump is in a rectangular pattern with an electrical
- second bump, an electrical third bump, and an electrical fourth bump, wherein the
- 6 polymer first mass is contiguous with only the electrical first bump, the electrical
- 7 second bump, the electrical third bump, and the electrical fourth bump; and
- 8 wherein the electrical first bump and the electrical second bump are in a
- 9 rectangular pattern with an electrical fifth bump and an electrical sixth bump,
- wherein the polymer second mass is contiguous with only the electrical first bump,
- the electrical second bump, the electrical fifth bump, and the electrical sixth bump.
- 1 17. The article of claim 10, wherein the electrical first bump includes a first
- 2 height, and wherein the polymer stress-relief layer includes a depth range against
- 3 the electrical first bump in a range from about 5 percent the first height to about 95
- 4 percent the first height.
- 1 18. A package comprising:
- a board including a bottom and a land side;
- a substrate including a lower surface and an upper surface, wherein the
- 4 board is disposed on the substrate land side:
- 5 a solder first bump disposed on the lower surface;
- a stress-relief layer disposed on the lower surface, wherein the solder first
- bump is at least partially embedded in the stress-relief layer, and wherein at least a
- 8 portion of the solder first bump is exposed above the stress-relief layer; and
- 9 a die dispose upon the upper surface.

- 1 19. The package of claim 18, wherein the stress-relief layer is a first stress-relief
- 2 layer, wherein the first stress-relief layer is disposed between the solder first bump
- and a solder second bump that is spaced apart and adjacent to the solder first bump,
- 4 the package further including:
- 5 a second stress-relief layer disposed between the solder first bump and a
- 6 solder third bump that is spaced apart and adjacent to the solder first bump.
- 1 20. The package of claim 18, wherein the solder first bump is in a rectangular
- 2 pattern with a solder second bump, a solder third bump, and a solder fourth bump,
- and wherein the stress-relief layer is disposed in about the geometric center of the
- 4 rectangular pattern.
- 1 21. The package of claim 18, wherein the solder first bump is in a rectangular
- 2 pattern with a solder second bump, a solder third bump, and a solder fourth bump,
- 3 and wherein the stress-relief layer is disposed contiguous with only the solder first
- 4 bump, the solder second bump, the solder third bump, and the solder fourth bump.
- 1 22. The package of claim 18, wherein the polymer stress-relief layer includes a
- 2 polymer first mass and a polymer second mass disposed upon the lower surface that
- 3 includes a ball grid array of at least six solder bumps:
- 4 wherein the solder first bump is in a rectangular pattern with a solder second
- 5 bump, a solder third bump, and a solder fourth bump, wherein the polymer first
- 6 mass is contiguous with only the solder first bump, the solder second bump, the
- 7 solder third bump, and the solder fourth bump; and
- 8 wherein the solder first bump and the solder second bump are in a
- 9 rectangular pattern with a solder fifth bump and a solder sixth bump, wherein the
- polymer second mass is contiguous with only the solder first bump, the solder
- second bump, the solder fifth bump, and the solder sixth bump.

- 1 23. The package of claim 18, wherein the solder first bump includes a first
- 2 height, and wherein the polymer stress-relief layer includes a depth range against
- 3 the solder first bump in a range from about 5 percent the first height to about 95
- 4 percent the first height.
- 1 24. A computing system comprising:
- 2 a microelectronic die;
- a mounting substrate including a lower and an upper surface;
- a solder first bump disposed on the lower surface;
- 5 a stress-relief layer disposed on the lower surface, wherein the solder first
- 6 bump is at least partially embedded in the stress-relief layer, and wherein at least a
- 7 portion of the solder first bump is exposed above the stress-relief layer;
- 8 a die disposed upon the upper surface and coupled to the solder first bump;
- 9 and
- 10 at least one of an input device and an output device coupled to the solder
- 11 first bump.
- 1 25. The computing system of claim 24, wherein the computing system is
- 2 disposed in one of a computer, a wireless communicator, a hand-held device, an
- 3 automobile, a locomotive, an aircraft, a watercraft, and a spacecraft.
- 1 26. The computing system of claim 24, wherein the die is selected from a data
- 2 storage device, a digital signal processor, a micro controller, an application specific
- 3 integrated circuit, and a microprocessor.